

LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)	ATTY DOCKET NO. 60889-5001	APPLICATION NO To be assigned
	APPLICANT Liu and Gregoire	
	FILING DATE Herewith	GROUP To be assigned

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
RL	US 2001/0017390 A1	08/30/01	Long et al. (published application no. 09/808,896)	257	368	
	US 2002/0011635 A1	01/2002	Abe et al.	257	408	
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	6,285,054	09/04/2001	Liu et al.	257	315	

FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
					YES NO

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

RL	Lee, W., Hwang, H., "Hot Carrier Degradation for Narrow Width MOSFET with Shallow Trench Isolation," Microelectronics Reliability, Received 07/13/1999, Revised 09/22/1999, 40 (2000), pp. 49-56

EXAMINER RL	DATE CONSIDERED 8/4/02
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	